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Taek-Soo Kim; Suezawa, K.; Yamaguchi, M.; Arai, K.; Shimada, Y.; Chong-Oh Kim; Magnetics, IEEE Transactions on Volume 37, Issue 4, Part 1, July 2001 Page(s):2255 - 2257  
Digital Object Identifier 10.1109/20.951140

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Munakata, M.; Yagi, M.; Motoyama, M.; Shimada, Y.; Baba, M.; Yamaguchi, M.; Arai, K.; Magnetics, IEEE Transactions on Volume 37, Issue 4, Part 1, July 2001 Page(s):2258 - 2260  
Digital Object Identifier 10.1109/20.951141

[AbstractPlus](#) | [References](#) | [Full Text: PDF\(120 KB\)](#) IEEE JNL**3. Sputter-deposited FeCoBC/AlN<sub>x</sub> multilayered film for wet-etching process**

Tomita, H.; Inoue, T.; Mizoguchi, T.; Sato, T.; Magnetics, IEEE Transactions on Volume 35, Issue 5, Part 2, Sept. 1999 Page(s):3571 - 3573  
Digital Object Identifier 10.1109/20.800593

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